



RADIATION TEST SUMMARY

PART TYPE : IRFY9140

DESCRIPTION : P-CHANNEL POWER MOSFET

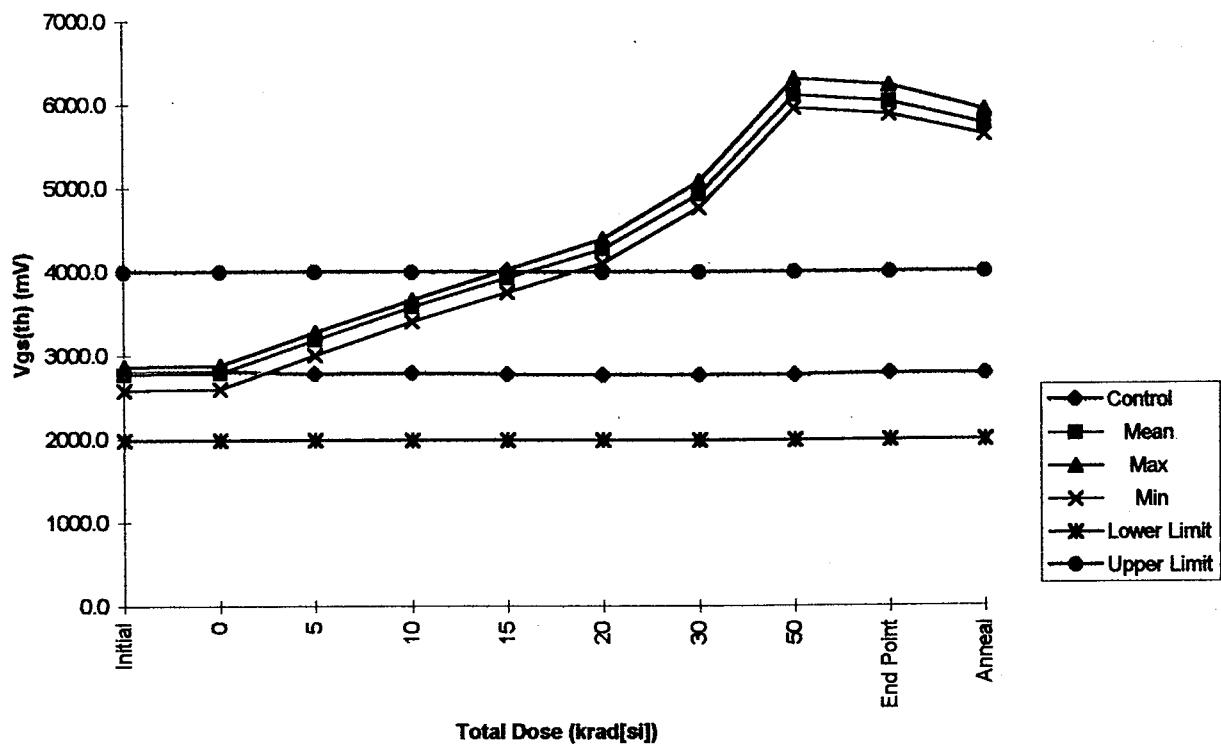
REPORT NO. : RD 248

PARAMETERS PLOTTED :

**VGS(th)
RDson**

NOTE : The results for the remaining parameters showed no significant change and hence plots were not considered necessary.

Radiation Results for Vgs(th)



Dose (kRad)	Control (mV)	Mean (mV)	Max (mV)	Min (mV)	Lower Limit (mV)	Upper Limit (mV)	Std.Dev.
Initial	2787.3	2782.8	2875.1	2590.1	2000	4000	130.03
0	2804.3	2799.7	2891.3	2604.7	2000	4000	131.36
5	2773.9	3198.4	3285.6	3011.2	2000	4000	127.11
10	2788.0	3593.2	3676.3	3413.1	2000	4000	123.01
15	2774.9	3943.2	4041.8	3766.9	2000	4000	123.01
20	2765.1	4287.2	4404.3	4121.1	2000	4000	120.76
30	2766.6	4944.4	5090.2	4779.4	2000	4000	128.79
50	2764.2	6116.6	6312.2	5961.7	2000	4000	145.63
End Point	2791.8	6041.3	6240.3	5889.3	2000	4000	146.10
Anneal	2783.7	5770.5	5936.5	5645.8	2000	4000	125.63

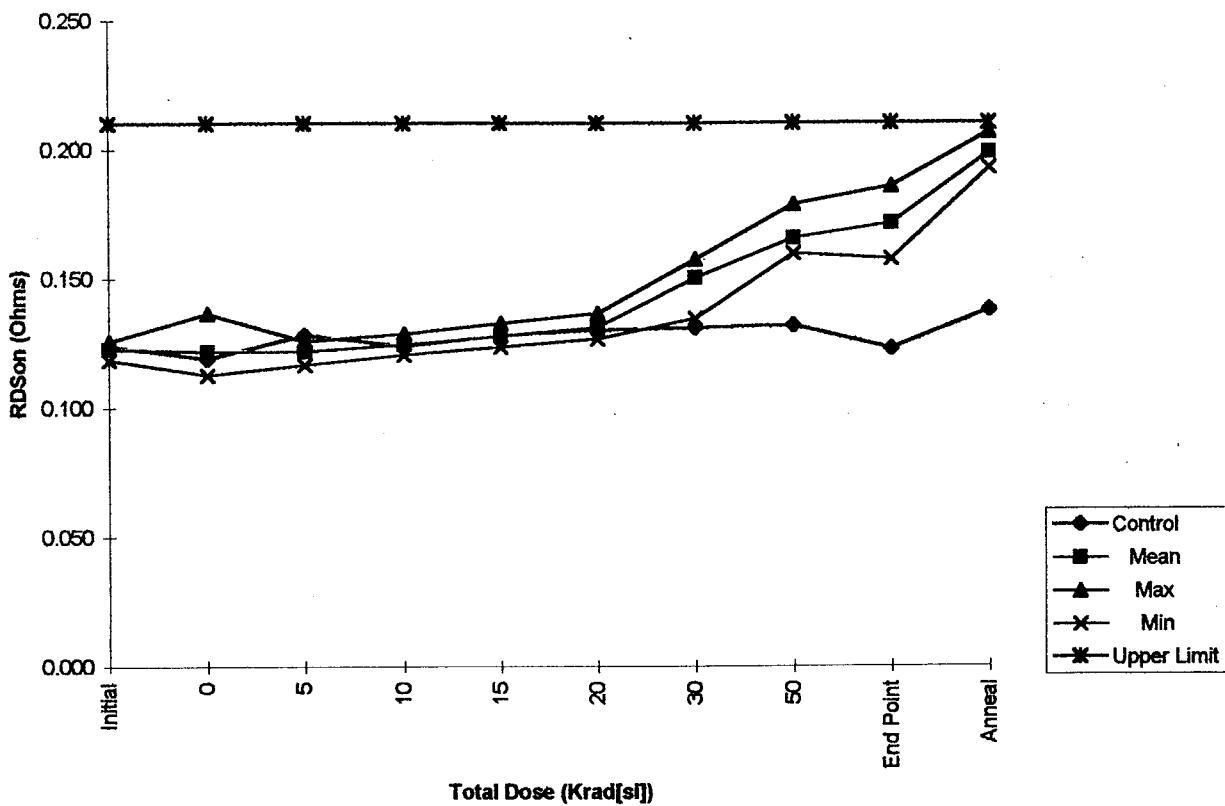
Note : Results for both control samples (biased and unbiased) similar therefore average plotted.

Lot size for statistics : 4 devices

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Radiation Results for RDson



Dose (kRad)	Control (Ohms)	Mean (Ohms)	Max (Ohms)	Min (Ohms)	Upper Limit (Ohms)	Lower Limit (Ohms)	Std.Dev.
Initial	0.124	0.123	0.126	0.119	0.210	-	0.00
0	0.119	0.122	0.137	0.113	0.210	-	0.01
5	0.128	0.122	0.126	0.117	0.210	-	0.00
10	0.124	0.125	0.129	0.121	0.210	-	0.00
15	0.128	0.128	0.133	0.124	0.210	-	0.00
20	0.130	0.132	0.137	0.127	0.210	-	0.00
30	0.131	0.151	0.158	0.135	0.210	-	0.01
50	0.132	0.166	0.179	0.160	0.210	-	0.01
End Point	0.123	0.172	0.186	0.158	0.210	-	0.01
Anneal	0.138	0.199	0.207	0.193	0.210	-	0.01

Note : Results for both control samples (biased and unbiased) similar therefore average plotted.

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RIR 79604

RD 248

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PO-PL-IGG-PL-0017

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Date: NA

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Component No. POIG003003B		Component Designation: TRANSISTOR, MOSFET, P-CHANNEL, POWER TYPE IRFY9140		Irradiation Spec No. NA Iss. Rev.	
Specifications Generic ESA/SCC 5000 Iss. 7 Rev. B Detail PO-PS-IGG-PL-0030 Iss. 3		Acceptance Evaluation Element Diffusion Lot	In-situ Remote	Project/Programme ENVISAT-1	
		6	7	8	9
Manufacturer: Name: Int. Rectifier Address: Hurst Green, Oxted Surrey, England		Test Facility: Name: ERA Address: LEATHERHEAD, SURREY ENGLAND			Originator: IGG CT Name: S THACKER
		10	11	12	
Radiation Source COBALT 60	Sample Size: Control Device: (Each Test)	4 14	Exposure Single Multiple	YES <input checked="" type="checkbox"/> NO <input type="checkbox"/>	Radiation Level: See Below
		13	15	16	17
Single Exposure Dose [Krad(Si)] Dose Rate [rad(Si)/s] Exposure Time Not applicable		18	Multiple Exposure: Irradiation Steps Dose [Krad(Si)] Dose Rate [rad(Si)/s] Exposure Time(s)	In accordance with the applicable Appendix to this Plan for each test.	
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Bias Requirements: During and after Exposure (for remote Electrical Measurements): YES

Bias Conditions:

Test Circuits: The Electrical Bias circuit is given in Figure 1 in the applicable Appendix to this Plan.

Shielding: Shielding is required to minimize dose enhancement effects caused by low energy, scattered radiation. The test units shall be enclosed in a Pb/Al container of Pb 1.5mm minimum, surrounding on inner shield of 0.7 to 1.0mm Al.

Irradiation Test Sequence(applied for each radiation test per the applicable Appendix to this plan). 21		
Test Step	Description	Requirements
1	Irradiation Test Samples Selection	Quantity 5 devices shall be selected from the lot delivered to IGG.
2	Serialisation	Serialisation - (if the devices are not already serialised) Test units shall be serialised 1 to 4 and the control unit shall be 5.
3	Initial Electrical Measurements (at IGG)	Per Table A herein - (Read-and-Record) - on all 5 parts at IGG. (See Remarks 1 and 2).
4	Initial Electrical Measurements (at ERA)	Per Table A herein - (Read-and-Record) - on all 5 parts at ERA. (See Remarks 1 and 2).
5	Set-up of Test	Verify Bias Circuit and Voltages (In-situ) for 4 test units.

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Irradiation Test Sequence (Cont.)

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Test Step	Description	Requirements
6	Irradiation Exposure	Verify radiation dose rate and position in the chamber to achieve required dose. Verify and witness duration of exposure to achieve required dose.
7	Intermediate Electrical Measurement (at ERA)	Bias to be maintained until test is performed. Test per Table A herein - (Read-and-Record) - on all 5 parts. Test to be performed immediately upon removal from chamber (less than 10 mins interval). Upon completion of test 4 test units shall be replaced in bias circuit and returned to chamber. Maximum interval between two consecutive exposures to be 30 mins. (See Remark 2).
8 to 7 + 3n	Repeat Set-up/Exposure/Test sequence upto a Final Total Dose as per the applicable Appendix	Repeat Steps 5, 6, 7 for a total of n cycles (see applicable Appendix). (See Remark 3)
8 + 3n	End Point Electrical Measurements (at IGG)	Per Table A herein - (Read-and-Record) - on all 5 parts at IGG. (See Remarks 2 and 4).
9 + 3n	Annealing	Bias shall be maintained during Annealing for 4 test units. Annealing shall be at room temperature for 168 hours.
10 + 3n	Final Electrical Measurements (at IGG)	Per Table A herein - (Read-and-Record) - on all 5 parts at IGG (See Remark 2).
11 + 3n	Total Dose Irradiation Test Report	ESA/SCC No. 22900

Remarks

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1. The initial electrical measurements performed at IGG (Test Step 3) shall be performed within 24 hours of the initial electrical measurements at ERA (Test Step 4).
2. All electrical testing shall be performed on the same set of equipment in order to achieve correlation of results both at IGG and ERA. All results plus details of any failures shall be advised to Project.
3. The set-up/exposure/test sequence shall be stopped for any device that exhibits repeated functional failure.
4. The End Point electrical measurements (Test Step 8 + 3n) performed at IGG shall be performed within 24 hours of the last electrical measurement at ERA (Test Step 7 + 3n).

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TABLE A - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE - $T_{amb} = +25 \pm 5^\circ\text{C}$ BEFORE, AT INTERMEDIATE POINTS, AND ON COMPLETION OF IRRADIATION.

NO.	CHARACTERISTICS	SYMBOL	MIL-STD-750 TEST METHOD	TEST CONDITIONS	LIMITS		UNIT
					MIN.	MAX.	
1	Breakdown Voltage Drain to Source	BV_{DSS}	3407 Bias Cond. C	$I_D = -0.25\text{mAdc}$ $V_{GS} = 0$	-100	-	Vdc
2	Gate Threshold Voltage	$V_{GS(th)}$	3403	$V_{DS} = V_{GS}$ $I_D = -1.0\text{mAdc}$	-2.0	-4.0	Vdc
3	Gate Current	I_{GSS}	3411 Bias Cond. C	$V_{GS} = -20\text{Vdc}$ $V_{DS} = 0$	-	-100	nAdc
4	Drain Current	I_{DSS}	3413 Bias Cond C	$V_{DS} = -100\text{Vdc}$ $V_{GS} = 0$	-	-0.25	mAdc
5	Drain Source ON Resistance	$r_{DS(ON)}$	3421	$V_{GS} = -10\text{Vdc}$ $I_D = -10\text{Adc}$ (Notes 2 and 3)	-	0.21	Ω

NOTES

1. The limits specified in this Table only apply to the first intermediate electrical measurements at dose 5Krad(Si). For all other intermediate, end point and final electrical measurements, these limits shall not apply but the tests shall be performed and the result recorded for information and characterisation purposes.
Parametric failures to the limits given in this Table could possibly occur at any irradiation level greater than 5Krad(Si).
2. Pulsed: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
3. Measured within 2mm of case.

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APPENDIX: 1**COMPONENT TYPE: IRFY9140**

This appendix defines the specific radiation test requirements applicable to the following ENVISAT-1 user(s):-

USER CODE**USER COMMENT**

MEICSA, MEVECI, SRDSSA, MPPSCO, SRICCR

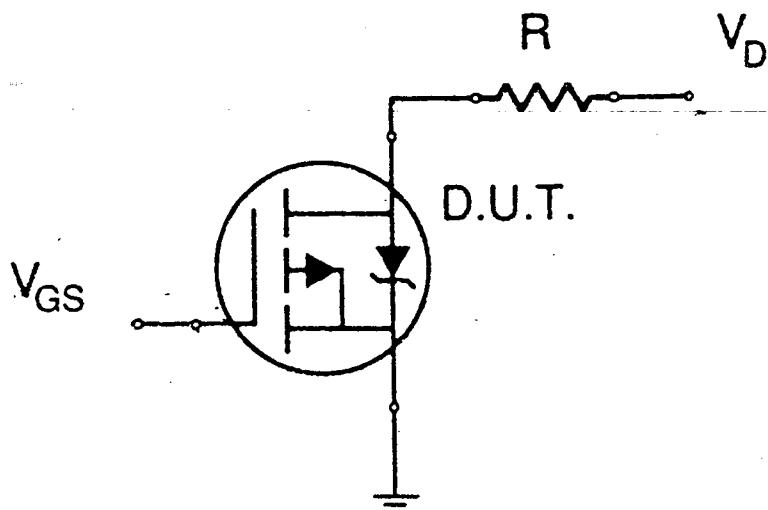
Ref. PO-DAS-1365/95

The following specific requirements shall apply:-

a) MULTIPLE EXPOSURE/IRRADIATION STEPS:

Irradiation Steps (n)	1	2	3	4	5	6
Dose [Krad(Si)]	5	5	5	5	10	20
Accumulated Dose[Krad(Si)]	5	10	15	20	30	50
Dose Rate [rad(Si)/s] (See note)	3	3	3	3	3	3
Exposure Time(s) (See note)	1667	1667	1667	1667	3333	1667

Note: The dose rates and exposure times given are nominal conditions and may be adjusted during irradiation testing to achieve convenient test points. The actual dose rate shall not exceed 3rad(Si)/s. The dose rates and exposure times used during the testing shall be recorded for each test step.

b) ELECTRICAL BIAS CIRCUIT FOR IRRADIATION TESTING:-

- NOTES:**
- i) Bias conditions $V_{GS} = -10\text{Vdc}$, $V_D = -30\text{Vdc}$
 - ii) $R = 300\Omega \pm 1\%$ to give $I_D = -100\text{mA dc}$

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F
RD248_IRFY9140_INIT_EMS @_IGG / V1.0 15/1/96 SMR

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Results file : RD248_IRFY9140_INIT_EMS @_IGG from: 11.11.97 / 09:45:23
Operator : PAUL RUSSELL
Part number : IRFY9140
Lot number : RD248
Order number : D/C 9730
Vendor : IR
: CONTROLS: 443(UNBIASED), 445(BIASED) ; 446,447,449,450
: INITIAL EMS @ IGG
: IRFY9140 PQ-PL-IGG-PL-0017 ISS.2 / V1.0 15/1/96 SMR

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Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)...	100.0	nA	
3. -IGSS (REV)	(0.0)...	100.0	nA	
4. -IDSS	(0)...	250	uA	
5. RDS on	(0.000)...	0.210	Ohm	
6. -V(BR)DSS	100.0	...	700.0	V

	443	445	446	447	449	450
1.1 [mV]	2795.6	2778.9	2875.1	2838.2	2580.1	2829.9
2.1 [nA]	1.5	1.5	1.4	1.6	1.5	1.6
3.1 [nA]	1.4	1.5	1.5	1.6	1.5	1.5
4.1 [uA]	0	0	0	0	0	0
5.1 [Ohm]	0.124	0.123	0.126	0.123	0.119	0.125
6.1 [V]	125.0	124.5	118.7	121.1	121.2	124.6

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F
RD248_IRFY9140_INIT_EMS @_ERA / V1.0 15/1/96 SMR

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Results file : RD248_IRFY9140_INIT_EMS @_ERA from: 12.11.97 / 10:23:23
Operator : PAUL RUSSELL
Part number : IRFY9140
Lot number : RD248
Order number : D/C 9730
Vendor : IR
: CONTROLS: 443(UNBIASED), 445(BIASED) ; RAD 446,447,449,450
: INITIAL EMS @ ERA
: IRFY9140 PO-PL-IGG-PL-0017 ISS.2 / V1.0 15/1/96 SMR

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Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)...	100.0	nA	
3. -IGSS (REV)	(0.0)...	100.0	nA	
4. -IDSS	(0)...	250	uA	
5. RDS on	(0.000)...	0.210	Ohm	
6. -V(BR)DSS	100.0	...	700.0	V

	443	445	446	447	449	450
1.1 [mV]	2813.6	2795.0	2891.3	2853.4	2804.7	2849.4
2.1 [nA]	1.2	1.2	1.2	1.2	1.3	1.3
3.1 [nA]	1.2	1.3	1.3	1.3	1.3	1.4
4.1 [uA]	0	0	0	0	0	0
5.1 [Ohm]	0.119	0.119	0.137	0.121	0.113	0.118
6.1 [eV]	124.4	123.7	118.2	120.6	120.4	124.0

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F
RD248_IRFY9140_EMS @_S_KRAD / V1.0 15/1/96 SMR

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Results file : RD248_IRFY9140_EMS @_S_KRAD from: 12.11.97 / 10:44:24
Operator : PAUL RUSSELL
Part number : IRFY9140
Lot number : RD248
Order number : D/C 9730
Vendor : IR
: CONTROLS: 443(UNBIASED), 445(BIASED) ; RAD 446,447,448,450
: EMS @ S KRAD
: IRFY9140 PO-PL-IGG-PL-0017 ISS.2 / V1.0 15/1/96 SMR

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Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)...	100.0	nA	
3. -IGSS (REV)	(0.0)...	100.0	nA	
4. -IDSS	(0)...	250	uA	
5. RDS on	(0.000)...	0.210	Ohm	
6. -V(BR)DSS	100.0	...	700.0	V

	443	445	446	447	449	450
1.1 [mV]	2805.3	2742.4	3285.6	3228.3	3011.2	3288.6
2.1 [nA]	1.5	1.5	1.5	1.4	1.3	1.4
3.1 [nA]	1.5	1.5	1.5	1.4	1.3	1.5
4.1 [uA]	0	0	0	0	0	0
5.1 [Ohm]	0.121	0.134	0.122	0.126	0.117	0.124
6.1 [V]	124.7	125.9	117.9	121.4	120.9	124.7

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F
RD248_IRFY9140_EMS @ 10_KRAD / V1.0 15/1/96 SMR

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Results file : RD248_IRFY9140_EMS @ 10_KRAD from: 12.11.97 / 11:37:49
Operator : PAUL RUSSELL
Part number : IRFY9140
Lot number : RD248
Order number :
Vendor :
:
: EMS @ 10 KRAD
:

=====

Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)...	100.0	nA	
3. -IGSS (REV)	(0.0)...	100.0	nA	
4. -IDSS	(0)...	250	uA	
5. RDS on	(0.000)...	0.210	Ohm	
6. -V(BR)DSS	100.0	...	700.0	V

443 445 446 447 448 450

1.1 [mV]	2800.3	2775.8	3667.6	3615.8	3413.1	3678.3
2.1 [nA]	1.4	1.4	1.5	1.5	1.5	1.5
3.1 [nA]	1.4	1.4	1.4	1.5	1.5	1.5
4.1 [nA]	0	0	0	0	1	1
5.1 [Ohm]	0.123	0.124	0.124	0.126	0.121	0.126
6.1 [V]	124.9	124.3	117.7	121.1	121.2	124.7

9./
SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F
RD248_IRFY8140_EMS_@_15_KRAD / V1.0 15/1/96 SMR

Results file : RD248_IRFY8140_EMS_@_15_KRAD from: 12.11.97 / 11:53:33
Operator : PAUL RUSSELL
Part number : IRFY8140
Lot number : RD248
Order number :
Vendor :
: EMS @ 15 KRAD
:

Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)...	100.0	nA	
3. -IGSS (REV)	(0.0)...	100.0	nA	
4. -IDSS	(0)...	250	uA	
5. RDS on	(0.000)...	0.210	Ohm	
6. -V(BR)DSS	100.0	...	700.0	V

	443	445	446	447	449	450
1.1 [mV]	2796.9	2752.9	4010.1	F1 3953.8	3768.9	4041.8 F1
2.1 [nA]	1.7	1.6	1.6	1.8	1.7	1.7
3.1 [nA]	1.7	1.6	1.6	1.7	1.6	1.6
4.1 [uA]	0	0	1	1	1	1
5.1 [Ohm]	0.124	0.131	0.126	0.129	0.124	0.133
6.1 [eV]	125.1	125.3	117.8	121.1	121.1	124.9

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F

RD248_IRFY9140_EMS_@_20_KRAD / V1.0 15/1/96 SMR

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Results file : RD248_IRFY9140_EMS_@_20_KRAD from: 12.11.97 / 12:11:54

Operator : PAUL RUSSELL

Part number : IRFY9140

Lot number : RD248

Order number :

Vendor :

 :

 : EMS @ 20 KRAD

 :

Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)...	100.0	nA	
3. -IGSS (REV)	(0.0)...	100.0	nA	
4. -IDSS	(0.0)...	250	uA	
5. RDS on	(0.000)...	0.210	Ohm	
6. -V(BR)DSS	100.0	...	700.0	V

	443	445	446	447	448	449	450
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1.1 [mV]	2793.4	2736.8	4336.7	F1	4286.5	F1	4121.1	F1	4404.3	F1
2.1 [nA]	2.2	2.4	2.3		2.3		2.3		2.4	
3.1 [nA]	2.1	2.2	2.1		2.2		2.1		2.2	
4.1 [uA]	0	0	1		1		2		2	
5.1 [Ohm]	0.125	0.135	0.129		0.133		0.127		0.137	
6.1 [V]	125.3	125.9	118.2		121.1		121.0		125.0	

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F
RD248_IRFY9140_EMS @ 30_KRAD / V1.0 15/1/96 SMR

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Results file : RD248_IRFY9140_EMS @ 30_KRAD from: 12.11.97 / 13:32:00
Operator : PAUL RUSSELL
Part number : IRFY9140
Lot number : RD248
Order number :
Vendor :
:
: EMS @ 30 KRAD
:

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Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)...	100.0	nA
3. -IGSS (REV)	(0.0)...	100.0	nA
4. -IDSS	(0)...	250	uA
5. RDS on	(0.000)...	0.210	Ohm
6. -V(BR)DSS	100.0	...	700.0	V

443 445 446 447 448 450

1.1 [mV]	2789.3		2743.9		4977.3	F	4930.5	F	4779.4	F	5090.2	F
2.1 [nA]	2.5		2.5		2.5		2.6		2.6		2.7	
3.1 [nA]	2.3		2.4		2.3		2.4		2.4		2.3	
4.1 [uA]	0		0		1		2		3		2	
5.1 [Ohm]	0.126		0.135		0.155		0.158		0.135		0.155	
6.1 [V]	125.4		125.8		118.1		121.3		121.4		125.1	

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F

RD248_IRFY9140_EMS_@_50_KRAD / V1.0 15/1/96 SMR

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Results file : RD248_IRFY9140_EMS_@_50_KRAD from: 12.11.97 / 14:14:42

Operator : PAUL RUSSELL

Part number : IRFY9140

Lot number : RD248

Order number :

Vendor :

: EMS @ 50 KRAD

:

Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)	...	100.0	nA
3. -IGSS (REV)	(0.0)	...	100.0	nA
4. -IDSS	(0)	...	250	uA
5. RDS on	(0.000)	...	0.210	Ohm
6. -V(BR)DSS	100.0	...	700.0	V

	443	445	446	447	449	450
1.1 [mV]	2789.2	2739.1	8112.8	F1 8079.8	F1 5961.7	F1 8312.2 F1
2.1 [nA]	2.6	2.6	3.0	3.2	2.7	3.3
3.1 [nA]	2.4	2.4	2.4	2.4	2.4	2.4
4.1 [uA]	0	0	2	3	4	3
5.1 [Ohm]	0.126	0.138	0.150	0.154	0.161	0.179
6.1 [V]	125.4	125.9	118.1	121.1	121.1	125.2

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SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F
RD248_IRFY9140-END_POINT_EMS / V1.0 15/1/96 SMR

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Results file : RD248_IRFY9140-END_POINT_EMS from: 13.11.97 / 13:38:35
Operator : PAUL RUSSELL
Part number : IRFY9140
Lot number : RD248
Order number :
Vendor :
:
: END POINT EMS
:

Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)...	100.0	nA	
3. -IGSS (REV)	(0.0)...	100.0	nA	
4. -IDSS	(0)...	250	uA	
5. RDS on	(0.000)...	0.210	Ohm	
6. -V(BR)DSS	100.0	...	700.0	V

	443	445	446	447	449	450	
1.1 [mV]	2800.2	2783.4	8028.2	F1 8007.2	F1 5889.3	F1 6240.3	F1
2.1 [nA]	2.3	2.3	2.6	2.7	2.4	2.8	
3.1 [nA]	2.2	2.2	2.1	2.2	2.2	2.2	
4.1 [uA]	0	0	3	3	3	3	
5.1 [Ohm]	0.123	0.122	0.172	0.171	0.158	0.198	
6.1 [V]	124.9	124.2	118.7	121.3	121.2	124.9	

SZ-TESTSYSTEME Statistics 03 Vers. 2.15 for TA07F
RD248_IRFY9140_FINAL_EMS / V1.0 15/1/96 SMR

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Results file : RD248_IRFY9140_FINAL_EMS from: 21.11.97 / 10:17:44
Operator : PAUL RUSSELL
Part number : IRFY9140
Lot number : RD248
Order number : D/C 9730
Vendor : IR
: CONTROLS: 443(UNBIASED), 445(BIASED) ; RAD 446,447,449,450
: FINAL EMS
: IRFY9140 PO-PL-I6G-PL-0017 ISS.2 / V1.0 15/1/96 SMR

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Test steps

1. -VGS	2000.0	...	4000.0	mV
2. -IGSS (FWD)	(0.0)...	100.0	nA	
3. -IGSS (REV)	(0.0)...	100.0	nA	
4. -IDSS	(0)...	250	uA	
5. RDS on	(0.000)...	0.210	Ohm	
6. -V(BR)DSS	100.0	...	700.0	V

	443	445	446	447	449	450	
1.1 [mV]	2795.8	2771.5	5791.0	F1 5708.7	F1 5645.8	F1 5936.5	F1
2.1 [nA]	1.8	1.8	2.0	2.1	1.8	2.1	
3.1 [nA]	1.7	1.7	1.7	1.7	1.7	1.7	
4.1 [uA]	0	0	3	2	3	2	
5.1 [Ohm]	0.149	0.127	0.198	0.207	0.193	0.198	
6.1 [V]	125.3	124.7	118.8	121.3	121.1	125.0	

I G G
Component
Technology

RECEIVING INSPECTION RECORD

RIR No: 79604

Section 1 Goods Inwards

Date	15Sep1997	Priority	19971231
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Supplier	INR/G INTERNATIONAL RECTIFIER G.B. Ltd.	Manu	INR/U INTERNATIONAL RECTIFIER	Doc	
Part Type	TRANSISTOR IRFY9140		Value	IRFY9140CSCS	
Spec No/Option	MIL-PRF-19500 IRFY9140CSCS		Issue	K - - 00	Date
PO No	CT12520 item 3	PO Qty	254 FLIGHT	Adv Qty	8

Section 2 Project Authorisation

Project/PLIN	000800 / 109906
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SAR No	N/A	Part Family	TRANSISTOR
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WAR No	Section 3 Results
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Related RIR Nos	Date Codes	9730	Act Qty	8
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Action	Reference	Qty Pass	Qty Rej	N C R	LOT QTY
Travel Visual	100%	8			18-9-11 100 108 CT
Visual Inspection	100%				
Solderability	-				
Data Review	100%				
Electrical Measurements	100%				
D P A	8				
Radiation	8 4+2 RD 248	6	-		

i.a.w.
Test Plan PD-PL-106-PL-0017/2 App.1.

Section 4 Disposition	Reference	Qty	Authorisation	Date
Project Store				
Reject-Credit/Replacement				
Scrap Store				
D P A (Report No)				
VOQ/Lot Acceptance				
Quarantine (Category)				
RADIATION TEST	RD 248	6	Ref	24/9/97

Section 6 Stores

Signed..... Date.....